**TI Designs: TIDA-01379**

**Transient Load Generator Reference Design**

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**Description**

This reference design permits to generate fast load transient signals required for the evaluation of converter stability. The board includes three separable load transient generators that are either regulated or not regulated and are able to support different load configurations. The loads can be referenced to ground or floating.

**Features**

- Fast Transients
- Floating and GND-Referenced Loads
- Regulated
- Isolated

**Applications**

- Power Supply Testing

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**Resources**

- TIDA-01379 Design Folder
- CSD17304Q3 Product Folder
- CSD25404Q3 Product Folder
- CSD18534Q5A Product Folder
- OPA365 Product Folder

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**Features**

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**Applications**

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1 System Description

Power supplies are present in all electronic devices where they power the needed supply rails. These rails need to be maintained at a certain level under the specified operating conditions, including load transient events. A load transient event happens when the load current changes suddenly from one level to another. The response of a converter to such changes permits to assess its stability.

The TIDA-01379 design board includes three different circuits that are used to perform load transient measurements for different load configurations. These circuits provide faster rise and fall times than commercial transient generators at a lower cost.

1.1 Key System Specifications

<table>
<thead>
<tr>
<th>PARAMETER</th>
<th>SPECIFICATIONS</th>
</tr>
</thead>
<tbody>
<tr>
<td>Load current</td>
<td>≥ 500 mA</td>
</tr>
<tr>
<td>Rise and fall time</td>
<td>&lt; 1 µs</td>
</tr>
<tr>
<td>Maximum load output voltage</td>
<td>20 V</td>
</tr>
</tbody>
</table>
2 System Overview

2.1 Block Diagram

Figure 1. TIDA-01379 Block Diagram
2.2 Highlighted Products

2.2.1 CSD17304Q3
The CSD17304Q3 device is a 30-V, N-channel, NexFET™ power MOSFET with the following features:
- Optimized for 5-V gate drive
- Ultra-low $Q_g$ and $Q_{gd}$
- Low thermal resistance
- Avalanche rated
- Pb-free terminal plating
For further details, see the CSD17304Q3 product page.

2.2.2 CSD25404Q3
The CSD25404Q3 device is a –20-V, P-channel, NexFET power MOSFET with the following features:
- Ultra-low $Q_g$ and $Q_{gd}$
- Low thermal resistance
- Low $R_{DS(on)}$
- Halogen free
- RoHS compliant
For further details, see the CSD25404Q3 product page.

2.2.3 CSD18534Q5A
The CSD18534Q5A device is a 60-V, N-channel NexFET power MOSFET with the following features:
- Ultra-low $Q_g$ and $Q_{gd}$
- Low thermal resistance
- Avalanche rated
- Logic level
- Pb-free terminal plating
For further details, see the CSD18534Q5A product page.

2.2.4 OPA365
The OPA365 device is a rail-to-rail input and output operational amplifier with a gain bandwidth of 50 MHz. This amplifier has a slew rate of 25 V/µs and can settle to 0.01% in 0.3 µs.

The OPA365 has the following features:
- Gain bandwidth: 50 MHz
- Zero-crossover distortion topology:
  - Excellent THD+N: 0.0004%
  - CMRR: 100 dB (minimum)
  - Rail-to-rail input and output
    - Input 100 mV beyond supply rail
- Low noise: 4.5 nV/√Hz at 100 kHz
- Slew rate: 25 V/µs
- Fast settling: 0.3 µs to 0.01%
- Precision:
  - Low offset: 100 µV
  - Low input bias current: 0.2 pA
• 2.2- to 5.5-V operation

For further details, see the OPA365 product page.

2.3 System Design Theory
The following sections present three ways to generate fast transient signals for converter stability tests. These designs provide transient signals with a rise and fall time of less than 1 µs for load steps from 0 to 500 mA with a limited bill of materials.

2.3.1 Open-Loop Load Transient Generator

Figure 2 and Figure 3 are open-loop load transient generators for ground-referenced positive or negative outputs. These generators are mainly composed of the following:
• An NMOS transistor for positive outputs
• A PMOS transistor for negative outputs
• A sense resistor to measure the load current

The transistors Q1 and Q2 are operated in their linear regions as variable resistors. The adjustment of the gate voltage permits to control the value of the resistance between drain and source, thereby setting the load current. A pulse waveform with the right levels must be applied on the IN pin to get the required load step. A pulse signal with a low duty cycle must be used to optimize the power dissipation on the transistor and the sense resistor and to avoid overheating of the board. Because this simple transient generator is always stable, it is recommended to use it for the first stability assessment of a converter when it is unknown if the converter is stable or not.

Figure 2. Open-Loop Load Transient Generator for Positive Outputs

Figure 3. Open-Loop Load Transient Generator for Negative Outputs
2.3.2 Regulated Load Transient Generator

The circuits presented in Section 2.3.1 are unregulated, and the user needs to estimate and set the gate voltage input that is needed for each required load steps. To avoid this manual tuning, the regulated load transient generator on Figure 4 is used. It is composed of mainly the following:

- An NMOS transistor
- An operational amplifier that is driving the gate of the transistor
- A transformer for galvanic isolation
- A sense resistor to measure the load current step

The gate of the transistor is driven by the amplifier and the feedback loop is between the transistor’s source and the negative input of the amplifier. The transient load that is applied to the device under test (DUT) is then proportional to the sense resistor value and the amplifier input voltage. In this TI Design, $R_{\text{SENSE}} = 1 \, \Omega$, which means that this design has a 1:1 equivalence between the control input voltage and the load step value.

A 1:1 transformer is added to isolate the input from the signal generator and to give the possibility to apply a transient to ground-referenced DUTs as well as floating DUTs. Adding this transformer creates overshoots and undershoots on the input signal applied to the non-inverting input of the amplifier. These are damped with the addition of a resistor (10 k\(\Omega\)) across the transformer’s secondary, which leads to some power loss.

To avoid that the transformer enters into saturation and a distortion of the input signal, 50% duty cycle pulse signals with symmetrical positive and negative levels must be used as input.

To select the amplifier, consider the following parameters to meet requirements in Table 1:

- Bandwidth $f_{\text{3dB}} > 0.35/\text{tr}$, with tr being the rise time of the input signal
- Slew rate that must be high enough to support the maximum rate of change of the amplifier’s output
- Supply voltage range that shall permit to reach the expected amplifier’s output voltage for the required maximum load
- Amplifier’s output load capability

Consider the following parameters when selecting the transformer:

- Input level that must allow to transmit the input signal without distortion
- Frequency range of operation and volt-microsecond rating. There must be enough time between the rising and falling edges of the pulse input signal to see the complete converter response.
3 Hardware, Testing Requirements, and Test Results

3.1 Hardware

The TIDA-01379 design board is composed of three different load transient generators that can be split up and used separately.

3.1.1 Connectors, Jumpers, and Test Points

Table 2, Table 3, and Table 4 give an overview of the connector and jumper connections of the evaluation board.

Table 2. Connector Overview Circuit 1

<table>
<thead>
<tr>
<th>CONNECTOR</th>
<th>SIGNAL</th>
<th>PIN</th>
<th>DESCRIPTION</th>
</tr>
</thead>
<tbody>
<tr>
<td>J1</td>
<td>VCC+</td>
<td>1, 2</td>
<td>Positive power supply</td>
</tr>
<tr>
<td>J2</td>
<td>GNDB</td>
<td>1, 2</td>
<td>Secondary ground or DUT negative output</td>
</tr>
<tr>
<td>J3</td>
<td>VCC-</td>
<td>1, 2</td>
<td>Negative power supply</td>
</tr>
<tr>
<td>J4</td>
<td>OUTP</td>
<td>1, 2, 3</td>
<td>DUT positive output</td>
</tr>
<tr>
<td></td>
<td>OUTN</td>
<td>4, 5, 6</td>
<td>DUT negative output</td>
</tr>
<tr>
<td>J5</td>
<td>VIN</td>
<td>1, 2</td>
<td>Signal generator input</td>
</tr>
<tr>
<td></td>
<td>GND</td>
<td>3, 4</td>
<td>Primary ground</td>
</tr>
<tr>
<td>J6</td>
<td>V_MEAS</td>
<td>1</td>
<td>Load transient voltage</td>
</tr>
<tr>
<td></td>
<td>GND</td>
<td>2</td>
<td>Secondary ground or DUT negative output</td>
</tr>
</tbody>
</table>

(1) Circuit 1 corresponds to the top part of the board with the title “Pos_Neg_Output”

Table 3. Connector Overview Circuit 2

<table>
<thead>
<tr>
<th>CONNECTOR</th>
<th>SIGNAL</th>
<th>PIN</th>
<th>DESCRIPTION</th>
</tr>
</thead>
<tbody>
<tr>
<td>J7</td>
<td>VOUT</td>
<td>1, 2, 3, 4</td>
<td>Negative output</td>
</tr>
<tr>
<td></td>
<td>S-</td>
<td>5</td>
<td>Negative output sense</td>
</tr>
<tr>
<td></td>
<td>GND</td>
<td>6, 7, 8, 9, 10</td>
<td>Ground</td>
</tr>
<tr>
<td>J8</td>
<td>S-</td>
<td>1</td>
<td>Negative output sense</td>
</tr>
<tr>
<td></td>
<td>GND</td>
<td>2</td>
<td>Ground</td>
</tr>
<tr>
<td>J9</td>
<td>VIN</td>
<td>—</td>
<td>Signal generator input</td>
</tr>
<tr>
<td>J10</td>
<td>V_MEAS</td>
<td>—</td>
<td>Load transient voltage</td>
</tr>
</tbody>
</table>

(1) Circuit 2 corresponds to the middle part of the board with the title “Neg_Output”

Table 4. Connector Overview Circuit 3

<table>
<thead>
<tr>
<th>CONNECTOR</th>
<th>SIGNAL</th>
<th>PIN</th>
<th>DESCRIPTION</th>
</tr>
</thead>
<tbody>
<tr>
<td>J11</td>
<td>VOUT</td>
<td>1, 2, 3, 4</td>
<td>Positive output</td>
</tr>
<tr>
<td></td>
<td>S+</td>
<td>5</td>
<td>Positive output sense</td>
</tr>
<tr>
<td></td>
<td>GND</td>
<td>6, 7, 8, 9, 10</td>
<td>Ground</td>
</tr>
<tr>
<td>J12</td>
<td>S+</td>
<td>1</td>
<td>Positive output sense</td>
</tr>
<tr>
<td></td>
<td>GND</td>
<td>2</td>
<td>Ground</td>
</tr>
<tr>
<td>J13</td>
<td>VIN</td>
<td>—</td>
<td>Signal generator input</td>
</tr>
<tr>
<td>J14</td>
<td>V_MEAS</td>
<td>—</td>
<td>Load transient voltage</td>
</tr>
</tbody>
</table>

(1) Circuit 3 corresponds to the bottom part of the board with the title “Pos_Output”
3.2 Testing and Results

The three different circuits are used to evaluate the load transient response of the TPS65632 device. The TPS65632 is a triple-output (V\textsubscript{POS}, V\textsubscript{NEG}, and AVDD) power supply used to drive AMOLED displays.

3.2.1 Test Setup

To evaluate the different circuits, a signal generator, an oscilloscope, and a power supply are required.

3.2.2 Test Results

3.2.2.1 Positive Output

The circuit in Figure 2 is used to evaluate the transient response of the VPOS boost converter. The load is connected between VPOS and GND as shown in Figure 5. Figure 6 shows that the converter is stable when a 500-mA load step with a rise and fall time of less than 250 ns is applied to it.

![Figure 5. Board 3 Connection](image-url)
3.2.2.2 Negative Output

The circuit in Figure 3 is used to test the transient response of the VNEG inverting buck-boost converter as shown in Figure 7. The load transient signal has an amplitude of 500 mA and a rise and fall time of less than 250 ns.

![Figure 6. Transient Response—Load Between VPOS and GND](image)

![Figure 7. Board 2 Connection](image)
3.2.2.3 Positive and Negative Outputs

The circuit in Figure 4 permits to generate a load transient signal for ground referenced loads as well as floating loads. It is used to test the stability of the TPS65632 converters when a 500-mA load step is applied between VPOS and GND, between VNEG and GND, and between VPOS and VNEG. Figure 9 shows how to connect the different loads. Figure 10, Figure 11, and Figure 12 show that the 500-mA load step has different rise and fall times values of 25 ns and 320 ns, respectively.
Figure 10. Transient Response—Load Between VPOS and GND

Figure 11. Transient Response—Load Between VNEG and GND
Figure 12. Transient Response—Load Between VPOS and VNEG
4 Design Files

4.1 Schematics
To download the schematics, see the design files at TIDA-01379.

4.2 Bill of Materials
To download the bill of materials (BOM), see the design files at TIDA-01379.

4.3 Layout Prints
To download the layer plots, see the design files at TIDA-01379.

4.4 Altium Project
To download the Altium project files, see the design files at TIDA-01379.

4.5 Gerber Files
To download the Gerber files, see the design files at TIDA-01379.

4.6 Assembly Drawings
To download the assembly drawings, see the design files at TIDA-01379.

5 Related Documentation

1. Texas Instruments, TPS65632 Triple-Output AMOLED Display Power Supply, TPS65632 Datasheet (SLVSCY2)
2. Texas Instruments, AN-1733 Load Transient Testing Simplified, SNOA507 Application Report (SNOA507)

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